Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10588631	DENOMME, GREGORY A.
Examiner	Art Unit
Young J Kim	1637

SEARCHED				
Subclass	Date	Examiner		

SEARCH NOTES				
Search Notes	Date	Examiner		
STIC-assisted search of SEQ ID Numbers 3 and 4 in commercial, issued- patent, and pre-grant patent publication databases	2/24/2009	/YJK/		
search parameters: standard cDNA search and size-limited oligomer search (word size max = 30)	2/24/2009	/YJK/		
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	2/24/2009	/YJK/		
see enclosed for text-search strategy	2/24/2009	/YJK/		

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/Young J Kim/ Primary Examiner.Art Unit 1637

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